

Notice of References Cited

Application/Control No.

10/074801 074850

Applicant(s)/Patent Under
Reexamination
HARDESTY ET AL.

Examiner

Anthony Weier

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,652,292	03-1972	Bach et al.	426/594
	B	US-4,985,271	01-1991	Neilson et al.	426/595
	C	US-6,048,567	04-2000	Villagran et al.	426/594
	D	US-6,207,203	03-2001	Atkinson et al.	426/73
	E	US-6,399,131	06-2002	Zeller et al.	426/520
	F	US-6,669,979	12-2003	Zhao et al.	426/595
	G	US-5,332,591	07-1994	Ogden, Ralph	426/386
	H	US-1,822,227	09-1931	LENDRICH LOUISE B P; et. al.	426/507
	I	US-4540591	9-1985	Dan et al	426/388
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 59-1375	01-1984	Japan	---	---
	O	JP 59-91845	05-1984	Japan	---	---
	P	JP 3-133368	06-1991	Japan	---	---
	Q	JP 11-32680	02-1999	Japan	---	---
	R	DE 19700368	09-1998	Germany	---	---
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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